

<b>Notice of References Cited</b>	Application/Control No. 10/051,774		Applicant(s)/Patent Under Reexamination HSU ET AL.	
	Examiner JOSEPH T. PHAN		Art Unit 2614	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,969,634	10-1999	Takashima et al.	340/7.34
*	B	US-6,389,271	05-2002	Kaneko, Shigeru	455/185.1
*	C	US-6,557,171	04-2003	Sonoda et al.	725/136
*	D	US-7,240,113	07-2007	Barry et al.	709/225
*	E	US-7,242,919	07-2007	Kim et al.	455/313
*	F	US-7,308,278	12-2007	Park, Jin-Young	455/503
*	G	US-7,310,496	12-2007	Schill et al.	455/3.04
*	H	US-7,436,825	10-2008	Jeong et al.	370/386
*	I	US-7,437,178	10-2008	Jeong et al.	455/525
*	J	US-7,450,933	11-2008	Kwak et al.	455/414.1
*	K	US-7,565,138	07-2009	Kim et al.	455/414.3
*	L	US-7,561,880	07-2009	Moon et al.	455/436
*	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.